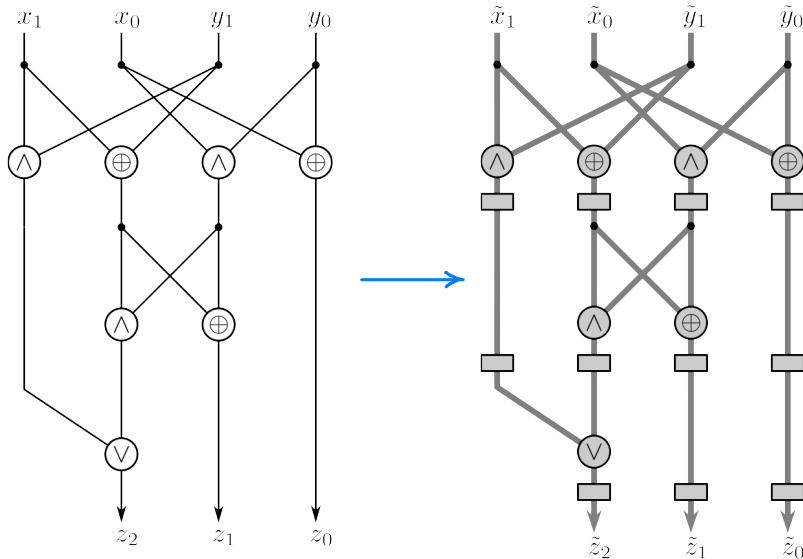


# Fault-tolerant computation (introduction)

## Fault-tolerant classical computation

Important requirement: Operations are done in parallel  
(because error correction should be performed periodically even on idle bits)

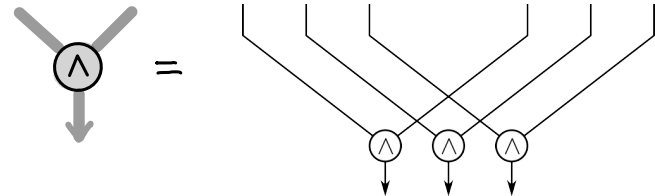
Simplifying assumption: Gates can be applied to arbitrary bit pairs (no locality constraints)



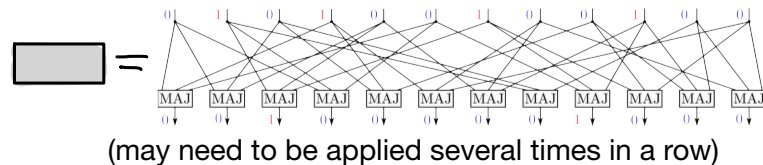
The fault-tolerant circuit consists of "gadgets":  
logical gates and error-correcting circuits

Repetition code:  $\tilde{x} = x^n$

Transversal implementation of logical gates



Error-correcting circuit



**Probabilistic fault model:** Each physical gate produces a wrong result with probability  $p$

(independently of other gates)

## Basic fact

Let  $0 < p < \epsilon < 1$ . If faults occur with probability  $p$ ,  
then the probability to have more than  $\epsilon m$  faults in  $m$  gates is exponentially small in  $m$ .

$$\begin{aligned} \Pr[\# \text{ of faults} > \epsilon m] &= \sum_{s > \epsilon m} \underbrace{\binom{m}{s}}_{2^{m H(s/m)}} p^s (1-p)^{m-s} \\ &\sim \sum_{s > \epsilon m} 2^{-m D(s/m \| p)} \sim 2^{-m D(\epsilon \| p)} \\ &\quad \text{because } D(q \| p) \text{ increases with } q \text{ for } q > p \end{aligned}$$

We will use this to prove

## Threshold theorem

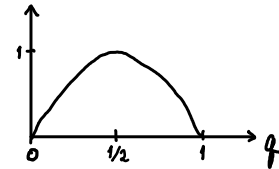
There exists some constant  $\epsilon > 0$  with the following property:

If faults in physical gates or idle bits occur with probability  $p < \epsilon$ ,  
then the overall error probability does not exceed  $L e^{-\alpha n}$ , where  
 $L$  is the number of logical gates and  $\alpha = \alpha(p) > 0$ .

logical  
fault rate

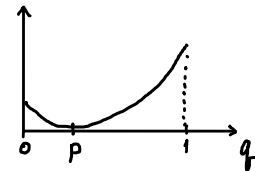
Entropy function:

$$H(q) = q \log_2 \frac{1}{q} + (1-q) \log_2 \frac{1}{1-q}$$



Relative entropy:

$$D(q \| p) = q \log_2 \frac{q}{p} + (1-q) \log_2 \frac{1-q}{1-p}$$



## Combinatorial error model

Within each gadget, we classify fault patterns into "acceptable" and "bad".

(The probability of a bad pattern should be small, but this condition is not part of the formal model.)

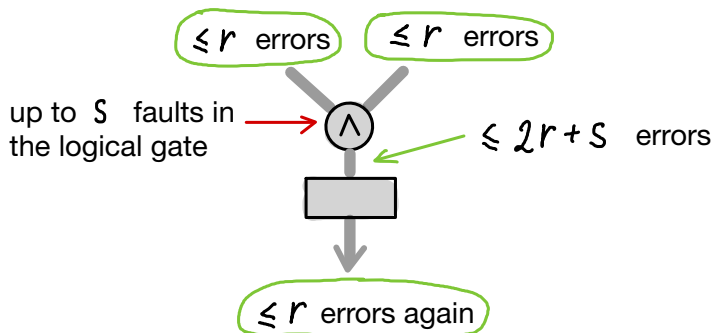
**Transversal logical gate:**  $s$  faults (in  $n$  simultaneously executed physical gates) are deemed acceptable

**Error-correcting circuit:** a fault pattern is acceptable if the action of the circuit satisfies the condition

$C(\ell, r)$ : If at most  $\ell$  input bits are in error, then at most  $r$  output bits are in error  $\left(r < \ell < \frac{n}{2}\right)$

This guarantees the correct operation, provided  $2r + s \leq \ell$

Specifically, there are at most  $r$  errors before each logical gate and after error correction



## Reduction of the probabilistic model to the combinatorial model and a proof of the threshold theorem (outline)

0) Choose suitable constants  $\epsilon$  (the admissible fraction of faulty gates),  $a, b, \dots$   
that would guarantee the success of the subsequent steps for  $n \rightarrow \infty$  (In practice, this is done after the analysis of those steps)

1) Construct an error-correcting circuit of size  $m=O(n)$  that satisfies the following conditions:

$A(a, b)$ : If there are no faults and  $\ell \leq an$  input bits are in error,  
then at most  $b\ell$  output bits are in error

$B$ : Each fault affects at most one output bit

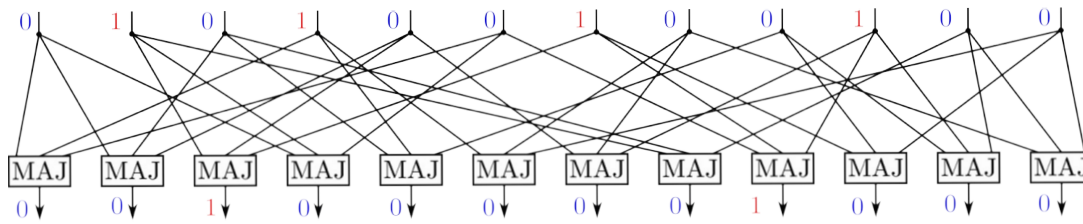
2) By using the previous circuit a constant number of times and allowing  $\epsilon m$  faults in each run,  
obtain an error-correcting circuit satisfying the condition  $C(a_+, a_-)$

We also allow  $\epsilon n$  faults in each transversal logical gate.

According to an earlier argument, this scheme works if  $2a_- + \epsilon \leq a_+$

Probability of a bad fault pattern:  $\sim 2^{-m D(\epsilon \| p)}$  or  $2^{-n D(\epsilon \| p)}$ , provided  $p < \epsilon$ .

## Constructing the error-correcting circuit



This picture shows a 3-voting circuit. We need a 5-voting circuit to satisfy the condition  $A(a, b)$

A 5-voting circuit  $MAJ_r$  is defined by choosing for each output bit  $j = 1, \dots, n$  and index  $t = 1, \dots, 5$  the corresponding input bit  $\Gamma_{jt} \in \{1, \dots, n\}$ .

### Lemma

There exist some constants  $0 < a < 1$ ,  $0 < b < 1$  such that for all sufficiently large  $n$ , there is a  $\Gamma$  such that

$$\text{If } |x| = \ell \leq an, \text{ then } |MAJ_r(x)| \leq b\ell \quad (*)$$

(equivalent to  $A(a, b)$ :  $x$  represents 0 in the repetition code with  $\ell$  errors)

$$x = \theta(X) \Leftrightarrow x_j = \begin{cases} 1, & \text{if } j \in X \\ 0, & \text{if } j \notin X \end{cases}$$

### Proof

the set of input errors

$\Gamma$  fails to satisfy condition  $(*)$  if and only if

subset of output errors

$$\exists \ell \leq an, \quad x = \theta(A) \quad \text{with } |A| = \ell, \quad B \quad \text{with } |B| = r := \lceil b\ell \rceil + 1$$

such that  $\forall j \in B, \quad MAJ_r(x)_j = 1$

$$\text{failure}(\Gamma) := \begin{cases} \exists l \leq an, & x = \theta(A) \text{ with } |A| = l, \quad B \text{ with } |B| = r := \lceil \frac{2}{3}l \rceil + 1 \\ \text{such that} & \forall j \in B, \quad \text{MAJ}_{\Gamma}(x)_j = 1 \end{cases}$$

If  $\Gamma$  is chosen randomly (with the uniform probability), then

$$\Pr_{\Gamma}[\text{failure}(\Gamma)] \leq \sum_{l=1}^{\lfloor an \rfloor} \sum_{A, B} \Pr_{\Gamma}[\text{failure}(\Gamma, A, B)]$$

3-voting?

$$\begin{aligned} \Pr_{\Gamma}[\text{failure}(\Gamma, A, B)] &= \prod_{j \in B} \Pr_{\Gamma}[\text{at least 3 of } \Gamma_{j_1}, \dots, \Gamma_{j_5} \text{ belong to } A] \\ &\leq \left( \binom{5}{3} \left( \frac{l}{n} \right)^3 \right)^r = 10^r \left( \frac{l}{n} \right)^{3r} \end{aligned}$$

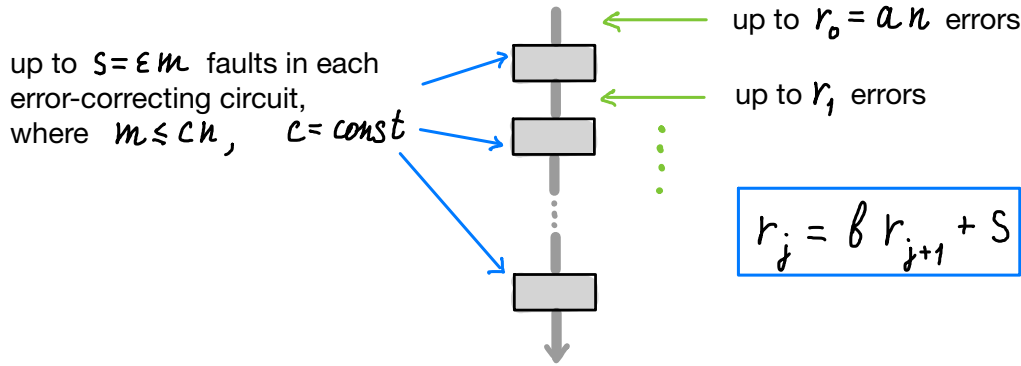
$$\begin{aligned} \sum_{A, B} \Pr_{\Gamma}[\text{failure}(\Gamma, A, B)] &\leq \binom{n}{l} \binom{n}{r} 10^r \left( \frac{l}{n} \right)^{3r} \\ &< \exp \left( \underbrace{l \ln \frac{ne}{l}}_{\ln \frac{n}{l} + \ln \frac{l}{r} + 1} + \underbrace{r \ln \frac{ne}{r}}_{\ln \frac{n}{l} + \ln \frac{l}{r} + 1} + r(\ln 10 + \underbrace{3 \ln \frac{l}{n}}_{\text{②}}) \right) \end{aligned}$$

$$\begin{aligned} \binom{n}{m} &= \frac{n \cdots (n-m+1)}{m!} \leq \frac{n^m}{m!} \\ &< \left( \frac{ne}{m} \right)^m \end{aligned}$$

$$= \exp \left[ -l \left[ \left( -1 + \underbrace{2 \frac{r}{l}}_{\text{①}} \right) \ln \frac{n}{l} - 1 - \left( \frac{r}{l} \ln \frac{l}{r} + 1 + \ln 10 \right) \right] \right] \leq \exp \left[ -l \left[ (2b-1) \ln \frac{1}{a} + f(b) \right] \right]$$

choose  $b = \frac{3}{4}$  and  $a$  sufficiently small

## Using the error-correcting circuit repeatedly



This basically works if  $r_0 \geq r_1 \geq \dots$ , but we will need a stronger condition

Steady state:  $r_\infty = b r_\infty + S \Rightarrow r_\infty = \frac{S}{1-b} = \frac{c}{1-b} \varepsilon n$

$S = \varepsilon cn$

A finite number of repetitions will satisfy the condition  $C(a_+, a_-)$  if  $a_+ = a$ ,  $a_- > \frac{r_\infty}{n} = \frac{c}{1-b} \varepsilon$

## Fixing the constants

$a > 0$ ,  $b = \frac{3}{4}$ ,  $c$  are determined by the 5-voting circuit

$a_+$ ,  $a_-$ ,  $\varepsilon$  are constrained as follows:  $a_+ = a$ ,  $a_- > \frac{c}{1-b} \varepsilon$ ,  $2a_- + \varepsilon \leq a_+$

These constraints can be satisfied by choosing a sufficiently small  $\varepsilon$ :  $\varepsilon < \left(1 + \frac{2c}{1-b}\right)^{-1} a$

## Some remarks about classical fault tolerance

- With repeated error correction (perhaps using different  $\Gamma$ s), 3-voting should work, but the proof will be more complex.
- Our relatively simple proof gives a very low (i.e. too pessimistic) estimate of the threshold. For a realistic estimate, more complex arguments and/or numerical simulation are needed.
- The exact threshold depends on the set of elementary gates used in the error-correcting circuit. Roughly,  $\xi \sim 0.1$

The quantum threshold is much lower, a few percent for fault-tolerant memory and something between  $10^{-3}$  and  $10^{-2}$  for universal computation.



# Quantum fault-tolerance

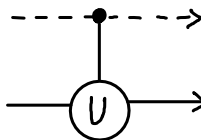
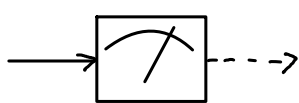
## Some convenient assumptions

- 1) The set of elementary physical operations includes the initialization of a qubit in state  $|0\rangle$

Not absolutely necessary, but error correction involves extracting (reduced) errors from the code and dumping them to the environment. This process is described by some non-unitary superoperator.

Extreme case of the amplitude damping channel:  $T\rho = \text{Tr} \rho \cdot |0\rangle\langle 0|$

- 2) We will assume that classical computation is reliable and fast
- 3) To utilize classical computation, we should use measurements and quantum gates with classical control. For example:



$$U = \sigma^x, \sigma^z, H, K, \dots$$

## Basic principles

- Encode each qubit using an ECC (typically, a stabilizer code)
- Use some logical gates that avoid exposing the logical qubit to the environment
- Run an error-correcting circuit after each logical gate

**Clifford + classical set of operations** (not universal but sufficient for correcting errors in stabilizer codes)

- 1) Initialization of a qubit in state  $|0\rangle$
- 2) Measurement in the  $|0\rangle, |1\rangle$  basis
- 3) Logical operations with classical bits
- 4) Classically controlled Clifford gates  $H, K, CNOT$

**Gottesman-Knill theorem:** In the absence of other gates, the above operations can be simulated classically in polynomial time

**Proof:** At each step, the quantum state is a stabilizer state:  $S_j |\xi\rangle = |\xi\rangle, \quad S_j = \pm \sigma(f_j), \quad j=1, \dots, n$

All elementary operations preserve this class of states. The only nontrivial operation is measurement.

When we measure any operator of the form  $S = \pm \sigma(g)$ , there are two cases:

- 1) If  $g \in D :=$  linear span of  $f_1, \dots, f_k$  over  $\mathbb{Z}_2$ , then  $S = (-1)^{\gamma_1} S_1^{\gamma_1} \dots S_k^{\gamma_k}$   
 $\Rightarrow$  the measurement outcome is  $\gamma$

- 2) Otherwise the measurement outcome is random, and the stabilizer set is updated as follows:

Let  $\gamma_j = \omega(f_j, g) \Leftrightarrow S_j S = (-1)^{\gamma_j} S S_j$ . Since (1) does not hold,  $\exists \ell$ ,  $S_\ell S = -S S_\ell$

$$\begin{aligned} S_\ell &\rightarrow S \\ S_j &\rightarrow S_j S_\ell^{\gamma_j} \quad \text{for } j \neq \ell \end{aligned}$$

$$(S_j S_\ell^{\gamma_j}) S = S_j (-1)^{\gamma_j} S S_\ell^{\gamma_j} = S (S_j S_\ell^{\gamma_j})$$

## **Fundamental problems** (compared to the classical case)

### 1) Not all logical gates can be realized transversally

- Self-dual CSS codes allow for the transversal realization of Clifford gates
- Some stabilizer codes allow for the transversal realization of some non-Clifford gates (at the expense of some Clifford gates)
- Eastin-Knill theorem: A universal set of logical gates cannot be realized transversally on any code of distance greater than 1

(Will show this later)

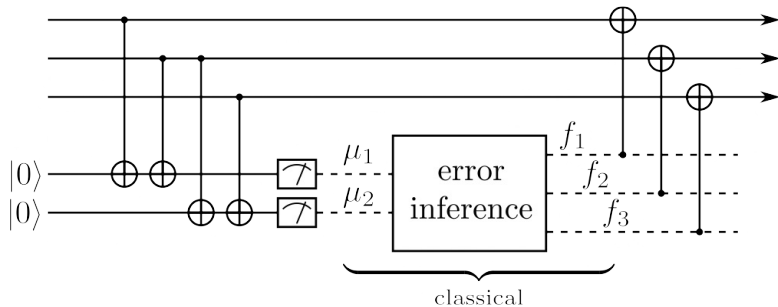
### 2) Error propagation: A fault in an error correcting circuit may affect multiple physical qubits

- Mitigation is possible but not straightforward

(Will do it on the next lecture)

## Problem with fault-tolerant syndrome measurement

Let us use the standard error correction method for a stabilizer code

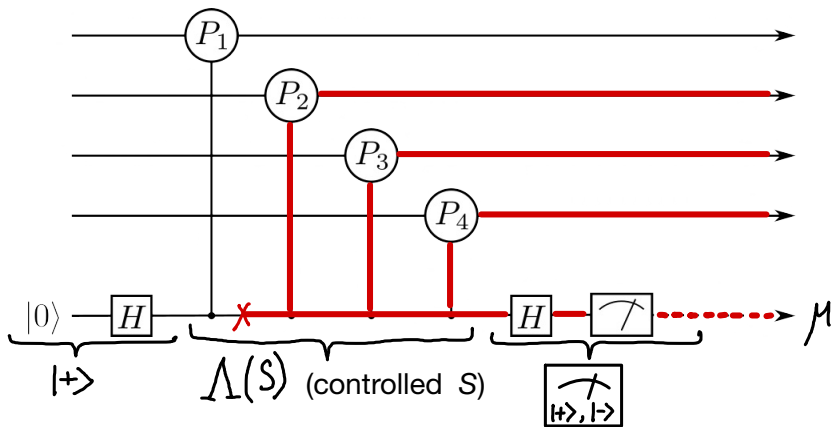


This particular circuit corrects bit flips in the quantum repetition code. In general, we need more syndrome bits.

Consider the eigenvalue measurement for

$$S = P_1 \cdots P_m$$

$$e.v.(S) = (-1)^M$$



-- A fault may result in an incorrect measurement outcome  $M$ . We can mitigate that by repeating the measurement 3 times.

-- A Z-error in the ancilla does not propagate

-- An X-error can propagate, affecting multiple code qubits.

$$E = P_2 P_3 P_4 = P_1 S \equiv P_1. \text{ The worst case is when the error hits in the middle, e.g. } E = P_3 P_4 \equiv P_1 P_2$$

## Plan for the next few lectures

- Quantum fault models
- Fault-tolerant error correction (avoiding error propagation) to implement quantum memory

We will construct error-correcting circuits for stabilizer codes such that:

- 1) If the input is in a correctable state in relation to the logical qubit (e.g., for a distance 3 code, at most one physical input qubit is in error) and there are no faults in the operation of the circuit, then the error is actually corrected.
- 2) If the input is in the code subspace (i.e. no input qubits are in error) and at most one fault happens, then the output is correctable.

Consequence: Unless two faults occur in adjacent error correction cycles, the encoded information remains intact

Logical error rate:

$$p_{\text{logical}} \sim O((np)^2)$$

- Threshold theorem for fault-tolerant memory and Clifford gates
- Adding non-Clifford operations (in particular "magic ancillas", e.g.  $\frac{1}{\sqrt{2}}(|0\rangle + e^{i\pi/4}|1\rangle)$ ) to achieve universality; implementing those operations fault-tolerantly